

KP Technology

COMPANY PROFILE



KP Technology is an award-winning company that designs and manufactures Kelvin Probe systems for work function and surface potential measurements. We supply state-of-the-art equipment and consultancy services to innovative companies and research institutes throughout the world. Our in house teaching laboratories ensure you get the best out of your system

The company was founded with the aim of bringing to the market new surface research tools that would allow specialists to investigate surface phenomena, provide equipment pathways for non-specialists and lastly to educate scientists, engineers and technologists in the capabilities of these emerging technologies.

Since inception in 2000 KP Technology has experienced rapid growth and now services over 100 companies and research institutes worldwide in their materials research and characterization requirements. Our team consists of electronic and software engineers, materials research associates, training, sales and administrative staff.

Prof. Iain D. Baikie is the CEO and company founder. He began developing Kelvin Probes for surface analysis in the early 1980's and has over 25 years experience with development and applications. Prof. Baikie is the inventor of the Off-Null, Height Regulated (ONtTHR) Kelvin Probe system.

Prof. Baikie has held tenure's at Universities and Research Institutes in Europe and USA and has previously been Chairman of a UK University Physics Group. He has published extensively in the fields of surface science and materials research and has pioneered introduction of modern educational tools in Physics Education.

The Baikie System

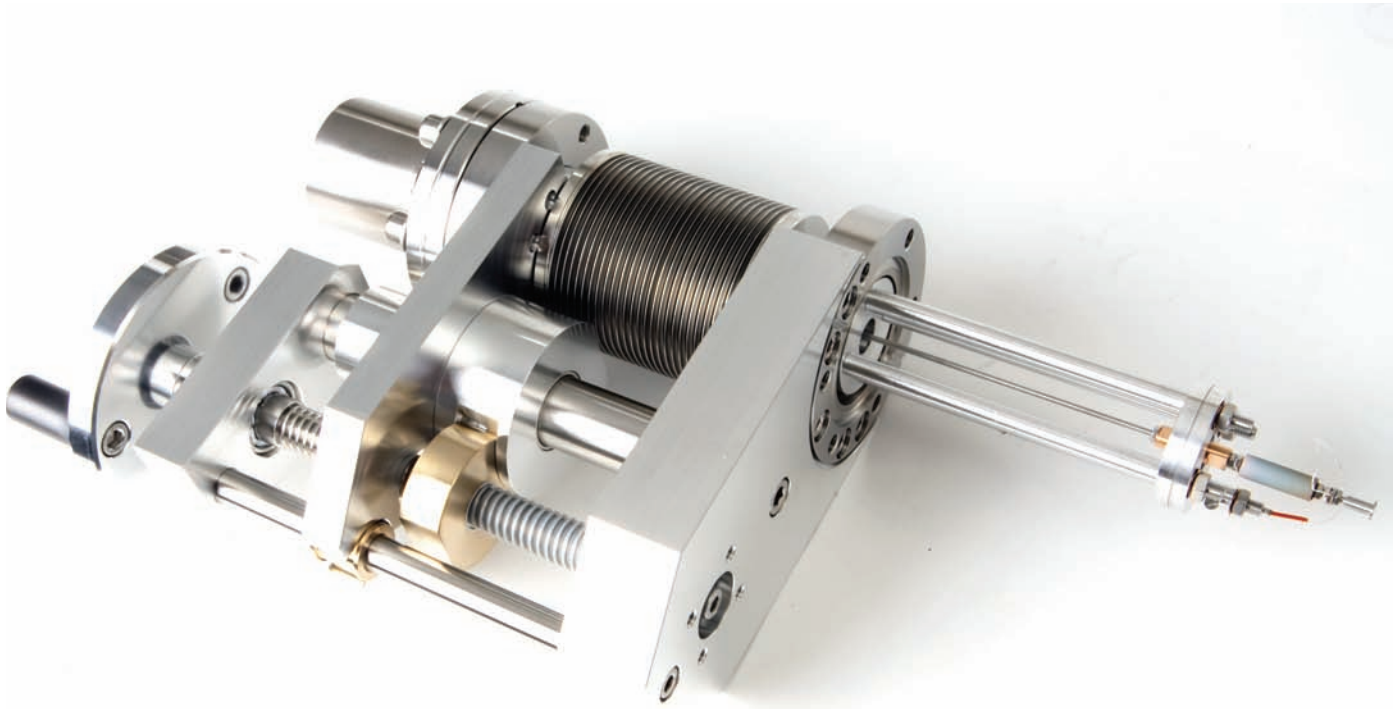
KP Technology systems are based upon unique features developed by Prof. Baikie, we are currently in our 7th Generation of design, with features unsurpassed by any other company:

- * Highest work function/surface potential resolution.
- * Off null and height regulation features invented by Prof. Baikie.
- * Full digital control of all Kelvin probe parameters.
- * High signal levels, patented signal processing.
- * Excellent system stability and repeatability.
- * Very high rejection of driver talkover noise compared with piezoelectric systems.
- * World's first commercial absolute Kelvin Probe system.
- * Quick change probe tip allowing user selectable spatial resolution.
- * Versatile equipment upgrade paths.
- * Our Signal-to-Noise (S/N) features remain unsurpassed in the field.
- * No expensive lock-in amplifier (LIA) is required.

Ultra High Vacuum Kelvin Probe System (UHV KP020)



The UHVKP020 is a complete Kelvin Probe solution for researchers investigating in UltraHigh Vacuum. This package includes everything the investigator needs to produce reliable accurate and repeatable data. In any one measurement upto 40,000 points can be recorded.



The UHVKP020 System Package includes the following components: UHV Kelvin Probe Head Unit , 50mm or 100mm Manual Translator, Sample Mount with Aluminium Sample, 3-Axis Motorised Translation Stage, Digital Control Unit (UHV Version), Data Acquisition System, NI-DAQ Software, Faraday Screen, Power Supply Unit, Dell PC with 17" Monitor & Associated Software

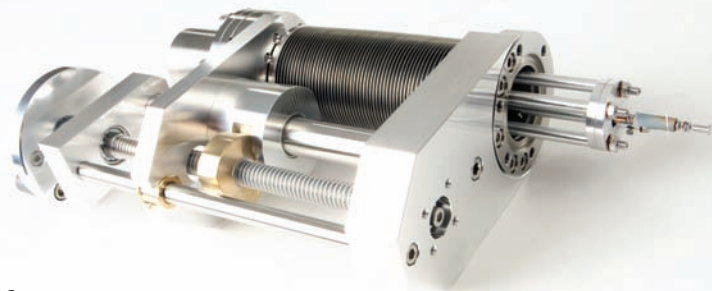


Ultra High Vacuum Kelvin Probe System (UHV KP020)



Tip Diameter:	4 - 10 mm (Other options available)
Work Function Resolution:	1-3mV
Vacuum Compatibility:	2 x 10 ⁻¹¹ mBar
Visualisation:	2D Maps of Surface Potential
PC:	Dell PC with Monitor and Pre-installed Software
Mounting Geometry:	Normal to Sample Surface
Mounting Port:	ICF 70 (2.75 inch) OD
Flange to Sample Distance:	User Defined
Manual Translation:	50 and 100 mm options
Digital Control:	Tip Amplitude, Frequency, Mean Spacing, Potential
Averaging:	Signal and Work Function Averaging
Detection System:	Off-Null with Parasitic Capacity Rejection
Data Acquisition System:	National Instruments (PCI-Card which is Pre-installed in PC)
Warranty:	24 Months
Motorised Translation:	Option

Shipping Housing with interchangeable
ambient calibration sample



Common Features

All our Kelvin Probe systems are controlled by a 7th Generation Hardware-Software combination termed the 'Baikie System'. This system, featuring digital control of all probe and detection parameter permits the operator to concentrate on sample analysis rather than technical issues. Our systems come complete with a Frequency Characteristic, Sample Measurements and Quick-Setup Parameter File.

Ultra High Vacuum Kelvin Probe System (UHV KP020)



Off-null (ON): the KP Technology ON signal detection system works on high signal levels and has an inherently higher resolution compared to null-based (LIA) systems. Null-based systems are prone to noise because the signal height is zero!

Height Regulation (HR): The KP Technology HR system controls the tip height during measurements and scans. Without this feature Work Function measurements will be affected by sample topography, be difficult to reproduce and prone to drift.

Fast Response Time: KP Technology systems are capable of measuring at a rate of 0.1 - 10 seconds. LIA systems typically use 10-30 second time constants to reduce noise.

Versatile Drives: KP Technology Voice-coil (VC) drives are highly stable in frequency, (unlike piezoelectric driving systems) and they are capable of much larger tip amplitudes, ideal parallel plate operation and supporting a range of tip sizes.